A Public Database of High-Temperature Superconductor Critical Current Data

Stuart C. Wimbush and Nicholas M. Strickland

Robinson Research Institute of Victoria University of Wellington, Wellington, New Zealand

Email: <u>Stuart.Wimbush@vuw.ac.nz</u>

Abstract—One of the major impediments to the industrial take-up of hightemperature superconductors is the paucity of comprehensive, reliable and relevant performance data on commercially available wires. To address this, the Robinson Research Institute is making available its internal database of wire performance data, acquired on our in-house 1 kA critical current measurement system. The database is freely accessible via the worldwide web at

https://figshare.com/collections/A high temperature superconducting HTS wire critic al current database/2861821 and allows download of both graphical images of the data as well as the underlying data files. The database will continue to be expanded into the future, and submissions of commercially available wires for independent characterization and inclusion are invited. We demonstrate the utility of this data in terms of a case study on the design of our 1.5 T 2G HTS MRI system and by outlining a comparison of correlations between low-temperature and 77 K performance across 2G HTS wires sourced from different manufacturers that demonstrates that this is useful only for wires of a particular type produced under similar conditions (for example, several batches produced using the same process). These examples highlight the need for complete characterization of different wires under the operating conditions of interest.

Keywords (Index Terms)— Critical currents, flux pinning, high-temperature superconductors, superconducting device engineering.

IEEE/CSC & ESAS SUPERCONDUCTIVITY NEWS FORUM (global edition), January 2017. Submitted September 16, 2016; Selected October 24, 2016. Reference ST546; Category 2, 5. This ASC 2016 manuscript 4MPo1C-07 was submitted to *IEEE Trans. Appl. Supercond.* for possible publication.